Search Notes				

Applica	ation/Control No.	Applicant(s)/Pat Reexamination	ent under
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SEARCHED			
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52	173.3	11/28/2006	ADF
136	246	11/28/2006	ADF
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INTERFERENCE SEARCHED			
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See EAST search history	11/28/2006	ADF
Inventor search	11/28/2006	ADF
Consulted with Jeffrey Barton and Nam Nguyen	11/28/2006	ADF
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